

parent case

Form PTO-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. M122-2393	PRIORITY SERIAL NO. 09/592,609		
				APPLICANT Fernando Gonzales	10/659,596		
				PRIORITY FILING DATE June 12, 2000	PRIORITY GROUP 2818		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
T	AA	5,398,449	03/98	Kikuchi	—	—	—
	AB	5,374,564	12/98	Bruel	—	—	—
	AC	5,855,693	01/99	Masari et al.	—	—	—
	AD	5,877,070	03/99	Goesle et al.	—	—	—
	AE	5,882,987	03/99	Srikrishnan	—	—	—
	AF	5,894,152	04/99	Jiao et al.	—	—	—
	AG	5,953,622	09/99	Lee et al.	—	—	—
	AH	6,004,406	12/99	Kobayashi et al.	—	—	—
	AI	6,309,945 B1	10/01	Sato et al.	—	—	—
	AJ	6,429,070 B1	03/02	Gonzalez et al.	—	—	—
	AK	6,384,439 B1	05/02	Walker	—	—	—
		6,423,992 B2	07/02	Fukuda, et al.	—	—	—
	AL	5,998,847	12/99	Assaderagli, et al.	—	—	—
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes      No
	AM						
	AN						
	AO						
	AP						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
T	AR		Goscar, U. et al., "Semiconductor Wafer Bonding: Science, Technology, and Applications", Electrochemical Society Proceedings				
			Vol. 97-36, (©1998), pp. 400-425, 436-445.				
	AS						
EXAMINER <i>[Signature]</i>			DATE CONSIDERED <i>7/22/04</i>				
<p><i>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</i></p>							

Form P-122-2393  <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b> <b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				ATTY. DOCKET NO. M122-2393		SERIAL NO. 10/859,596	
				APPLICANT Fernando Gonzales			
				FILING DATE Sept. 9, 2003 (RCE filed herewith)		GROUP 2818	
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
TL	AA 6,251,754	06/01	Ohshima et al.	—	—		
TL	AB 6,245,161 ✓	06/01	Henley et al.	—	—		
TL	AC 5,374,581	12/94	Ichikawa et al.	—	—		
TL	AD 4,891,329	01/90	Reisman et al.	—	—		
TL	AE 6,150,031 ✓	11/00	Yonehara	—	—		
TL	AF 6,083,324 ✓	07/00	Henley et al.	—	—		
AG							
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AM							
<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date	Country	Class	Subclass	Translation	
AN						Yes	No
AO							
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<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
	AS						
	AT						
EXAMINER <i>Thul</i>			DATE CONSIDERED <i>7/30/05</i>				
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